

## Sunday, 24 November 2002

16:00 – 18:00	Registration
18:00 – 20:00	Welcome party at the International House of Japan

## Monday, 25 November 2002

9:30 – 9:50	Opening remarks by the workshop chairman S. Ushioda
<b>Plenary Session, chair: S. Ushioda</b>	
9:50 – 10:35	K. Takayanagi, Tokyo Institute of Technology, Quantum Nanowires: Super nanoprobe UHV electron microscopy combined with STM
10:35 – 10:55	coffee break
<b>Session TEM, chair: N. Yamamoto</b>	
10:55 – 11:30	Y. Tanishiro, Tokyo Institute of Technology , Energy-filtered reflection electron microscopy, diffraction and interferometry: surface plasmon excitation and coherence
11:30 – 12:05	S. Frabboni, University of Modena, Application of Energy Filtered Convergent Beam Electron Diffraction to 2-D strain mapping in silicon
12:05 – 12:40	C. Oshima, Waseda University, Coherent Electron Beams from Carbon Nanotubes
12:40 – 14:30	lunch break
<b>Session CL, chair: T. Sekiguchi</b>	
14:30 – 15:05	N. Yamamoto, Tokyo Institute of Technology, Optical Properties of Nano-structures in Semiconductors studied byTEM- CL Technique
15:05 – 15:40	T. Sekiguchi, National Institute for Materials Science, Characterization of widegap semiconductors and their nanostructures by CL/EBIC
15:40 – 16:15	G. Salviati, IMEM-CNR Institute, Depth resolved and power dependent SEM-CL study of GaN/AlAn/Si stacked QDs
16:15 – 16:35	coffee break
<b>Session STM I, chair: S. F. Alvarado</b>	
16:35 – 17:10	R. Berndt, IEAP Christian-Albrechts- Universität, STM-based Spectroscopies of Excited Electronic States
17:10 – 17:45	Y. Uehara, Tohoku University, Identification of surface adsorbates by scanning tunneling microscope light emission spectra
17:45 – 18:05	S. Kazaoui, Nanotechnology Research Institute, Photo-induced tunneling current in single-wall carbon nanotubes investigated by scanning tunneling spectroscopy

**Tuesday, 26 November 2002**

Session Spectromicroscopy I, chair: Y. Watanabe	
9:30 – 10:05	S. Heun, Sincrotrone Trieste, AFM local anodic oxidation studied by spectroscopic microscopy
10:05 – 10:40	M. Oshima, University of Tokyo, Photoelectron Emission Microscopy for Magnetic Micro/Nanostructures
10:40 – 11:00	coffee break
Session Spectromicroscopy II, chair: M. Kiskinova	
11:00 – 11:35	N. Ueno, Chiba University, Combined PEEM and MEEM study of organic/metal interfaces
11:35 – 12:10	T. Kinoshita, University of Tokyo, Photoemission electron microscopic studies at the Photon Factory
12:10 – 12:30	M. Iwami, Okayama University Spectroscopic structural studies of metal/SiC system
12:30 – 14:30	lunch break
14:30 – 18:00	Excursion to Research Center for Advanced Science and Technology (RCAST), the University of Tokyo, Komaba campus
19:00 – 21:00	Banquet at YEBISU “BEER STATION”
– 21:30	The International House of Japan

**Wednesday, 27 November 2002**

<b>Session Spectromicroscopy III, chair: N. Ueno</b>	
9:30 – 10:05	M. Kiskinova, Sincrotrone Trieste, Chemical specific imaging and micro-spectroscopy: recent achievements and future projects
10:05 – 10:40	S. Suzuki, NTT Basic Research Laboratories, Photoemission spectromicroscopy of carbon nanotubes
10:40 – 11:00	coffee break
<b>Session Spectromicroscopy IV, chair: S. Heun</b>	
11:00 – 11:35	M. Bertolo, Sincrotrone Trieste, Photoemission spectromicroscopy studies of superconductor surfaces
11:35 – 11:55	T. Munakata, The Institute of Physical and Chemical Research (RIKEN), Occupied and unoccupied states on sub- $\mu$ m surface area measured with a laser based photoemission micro-spectrometer
11:55 – 12:30	T. Koshikawa, Osaka Electro-Communication University, Dynamic Observation of Nano-structure Formation by Cathode Lens Microscopy
12:30 – 14:30	lunch break
<b>Session STM II, chair: R. Berndt</b>	
14:30 – 15:05	S. F. Alvarado, IBM Zurich Research Laboratory, Nano-scale excitation-spectroscopy and interface studies of semiconducting materials using the STM
15:05 – 15:40	H. Yamaguchi, NTT Basic Research Laboratories, Structural and Electrical Characterization of InAs/GaAs(111)A Heterostructures by Scanning Tunneling Microscopy and Spectroscopy
15:40 – 16:15	R. Phaneuf, University of Maryland, Correlation of Time Response and Spectroscopy in STM Measurements of Devices
16:15 – 16:35	M. Sakurai, National Institute for Materials Science, Inelastic scattering process in electron transport from a metal tip through nanostructures into a GaAs(110) surface
16:35 – 16:55	coffee break
<b>Poster Session</b>	
16:55– 18:30	Lecture room D

## Thursday, 28 November 2002

Session SNOM I, chair: Y. Takiguchi	
9:30 – 10:05	K. Miyano, University of Tokyo, Spectroscopy of individual metal nanoparticles
10:05 – 10:40	M. Colocci, Università di Firenze, Light transport in nanostructured materials
10:40 – 11:00	coffee break
Session SNOM II, chair: K. Miyano	
11:00 – 11:35	S. Kawata, Osaka University, Tip-enhanced Near-field Raman Spectroscopy
11:35 – 12:10	Y. Takiguchi, Hamamatsu Photonics K.K., Advanced photonics for nano-technology
12:10 – 12:30	H. Oikawa, National Institute for Materials Science, Scanning near-field optical microspectroscopy of perylene nanocrystals
12:30 – 14:30	lunch break
Special Session, chair: G. Salviati	
14:30 – 14:45	A. Volpi from Italian Embassy
Session Nanostructures, chair: G. Salviati	
14:45 – 15:20	D. Pisignano, National Nanotechnology Laboratory of INFM, Soft nanolithography for inorganic and molecular patterning
15:20 – 15:55	S. Modesti, University of Trieste, Structure and electronic properties of nanostructures in GaAs by cross-sectional scanning tunneling microscopy and spectroscopy
15:55 – 16:15	T. Takahashi, University of Tokyo, Photo-absorption in InAs Nanostructures Studied by Light-illuminated STM
16:15 – 16:35	Y. Sakuma, Fujitsu Laboratories Limited, InGaAs Quantum Wires on {111}B-Faceted V-Grooves of InP Formed by In-Situ Gas Etching and MOCVD Regrowth
16:35 – 16:50	Concluding remarks by the workshop vice-chairman G. Salviati

## Friday, 29 November 2002

10:00 –	Excursion to NTT Basic Research Laboratories “Satellite Workshop on Surface- & Nano-Science in NTT”
11:30 – 19:00	Lunch service, several presentations, lab tour, and buffet style party
– 20:30	The International House of Japan

**Poster**

P1	L. Sirghi, Shizuoka University, Wetting Dynamic in Friction Force Microscopy in Air
P2	A. Patnaik, Chiba University, Self-organization of C <sub>60</sub> nano-aggregates in solvents of varying dielectric constant
P3	A. Ishii, Tottori University, The first principles computational study on the new technology for termination of semiconductor surface with atomic nitrogen
P4	Y. Sakai, Ashiya University, Trapped Electrons in a Defective TiO <sub>2</sub> (110) Surface Observed by Scanning Tunneling Spectroscopy
P5	Y. Teraoka, Japan Atomic Energy Research Institute, Roles of incident energy of O <sub>2</sub> molecules as a control parameter for Si(001) oxidation in a surface temperature region higher than 860 K
P6	M. Ishii, Japan Synchrotron Radiation Research Institute (JASRI), Inner-shell and valence double microspectroscopy by single scanning probe: Simultaneous analysis of atomic structure and micro-device characteristics
P7	T. Ohgi, University of Tsukuba, Single electron charging effects in supported nanoclusters studied by tunneling and photoelectron spectroscopy
P8	T. Mitsui, National Institute for Materials Science, Comparison of cathodoluminescence and scanning near field optical microscopy for the study of semiconductor quantum dots
P9	T. Tsuruoka, Tohoku University, Real-space observation of electron thermalization process in AlGaAs/GaAs quantum well structures using scanning tunneling microscope
P10	M. Hoshino, Tokyo Institute of Technology, STM Light Emission from p-type GaAs(110) Surface